

Beam-Beam Simulation with Electron Lens at RHIC

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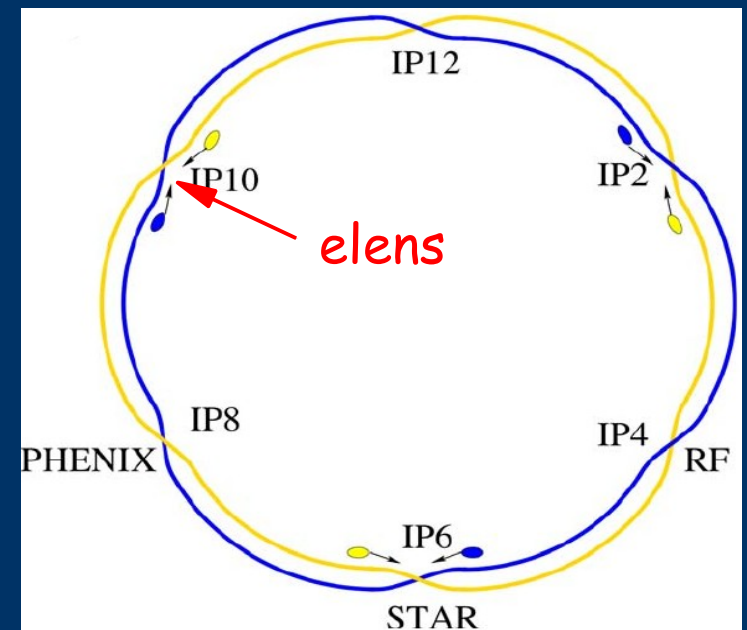
CM12, Apr 9, 2009

Motivation

- To compensate large tune spread and emittance growth due to head-on interactions in proton-proton run at RHIC, an electron lens with a Gaussian transverse profile was proposed.
- Using a weak-strong code BBSIMC, we investigate effects of electron lens on tune change and beam loss.
 - Figures of merit:
 - tune footprint
 - Dynamic aperture
 - Tune diffusion
 - Particle losses

MODEL: Electron lens simulation at RHIC

- 250 GeV p-p beam
- 2 head-on (IP6 & 8), $\beta = 0.5\text{m}$
- Beam intensity: 2×10^{11} per bunch
- Working point: (0.695, 0.685)
- 1 e-lens at IP10, $\beta = 10\text{m}$
- NL: sextupoles/IR multipoles



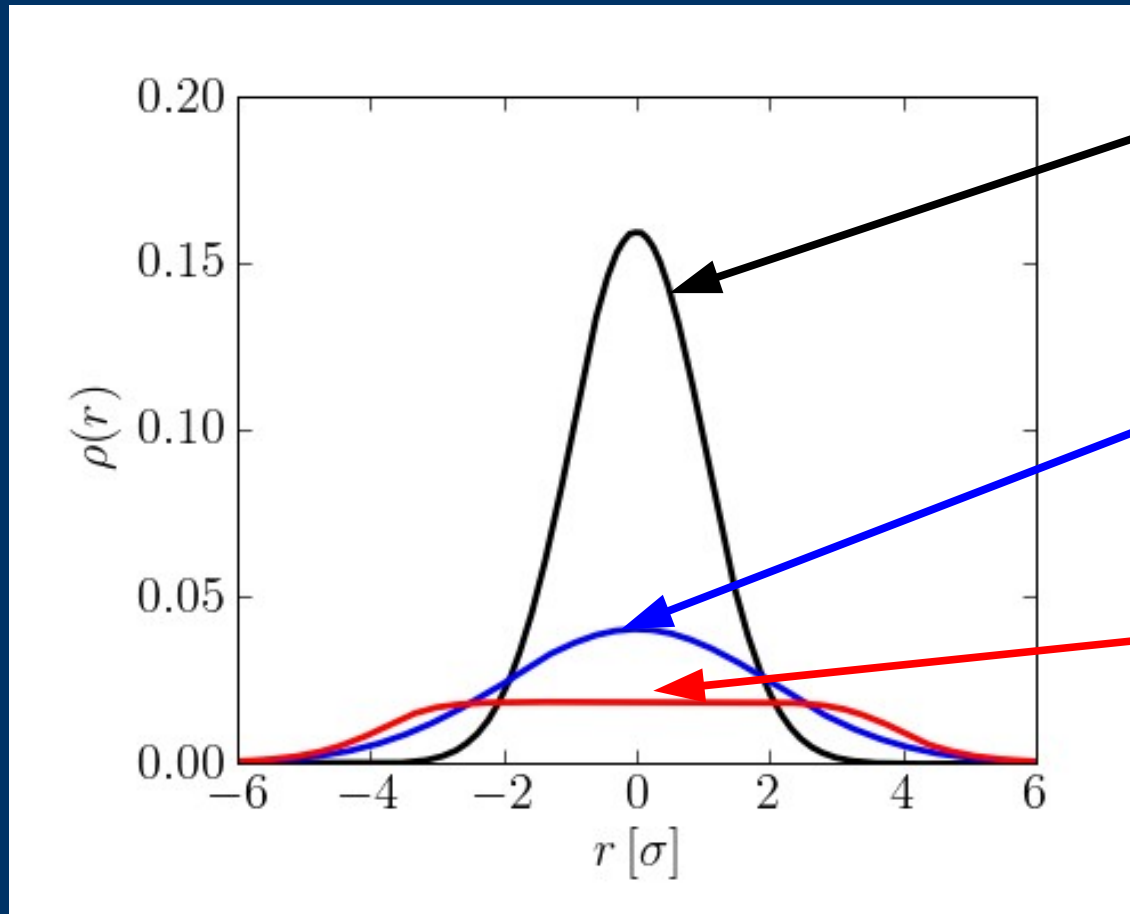
BBSIMC

- 6D weak-strong tracking code
- Linear transfer matrices between nonlinear elements
- E-lens is considered as a thin element
 - Gaussian electron beam
 - Smooth Edge Flat Top (SEFT)
- <http://www-ap.fnl.gov/~hjkim>

Electron Lens Requirement

- **For full tune-spread compression**
 - Electron beam profile should match proton profile at IP (Gaussian)
 - Electron beam intensity should be $N_e = N_{ip} * N_p$; $N_{ip} = 2$, $N_p = 2E11$
 - Full tune-spread compression does not help to reduce particle loss (BBSIMC, LIFETRAC, SIXTRACK)
 - **For reduction of particle loss**
 - Electron beam profile should match proton profile for tune compression, but other profiles may be more suitable for reducing particle loss.
 - Electron beam intensity may be different from $N_{ip} * N_p$
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Electron beam profiles



1 sigma Gaussian

- $\exp(-0.5(r/\sigma)^2)$
- match to proton beam size

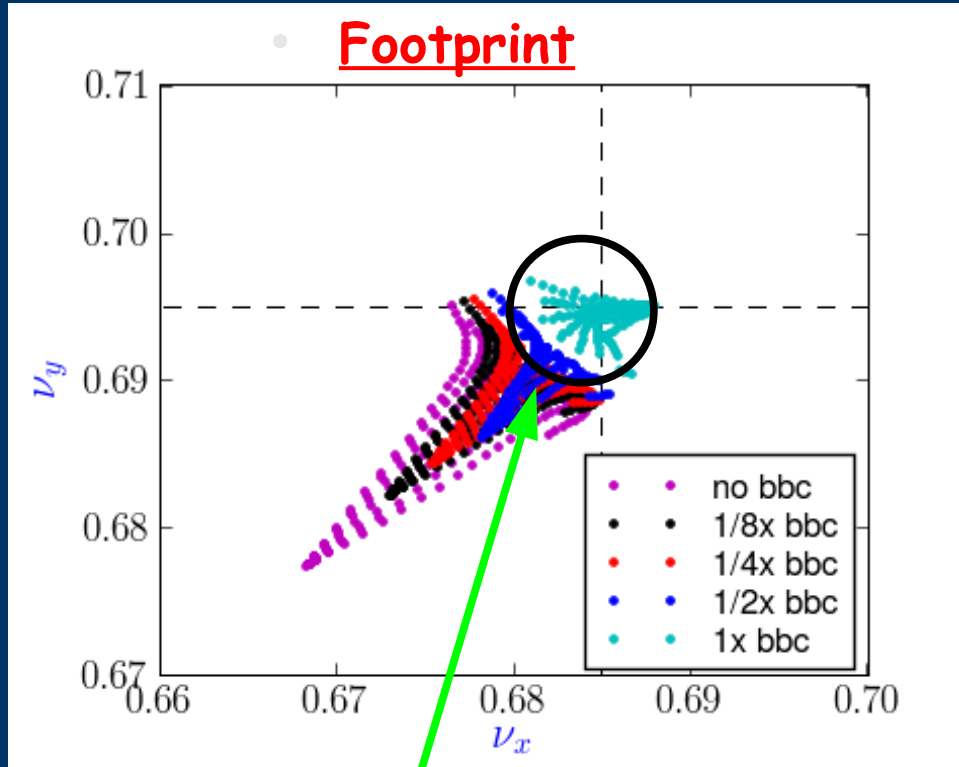
2 sigma Gaussian

- $\exp(-0.5(r/2\sigma)^2)$

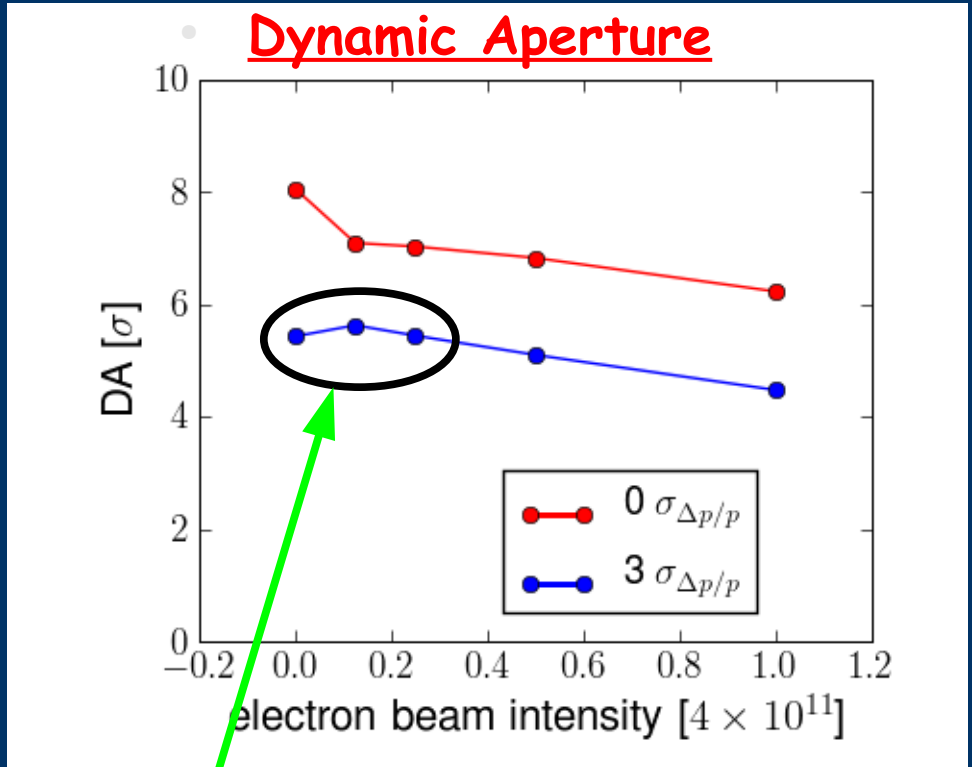
Smooth Edge Flattop

- $1/(1+(r/4\sigma)^8)$

Gaussian Electron Lens (1 sigma)



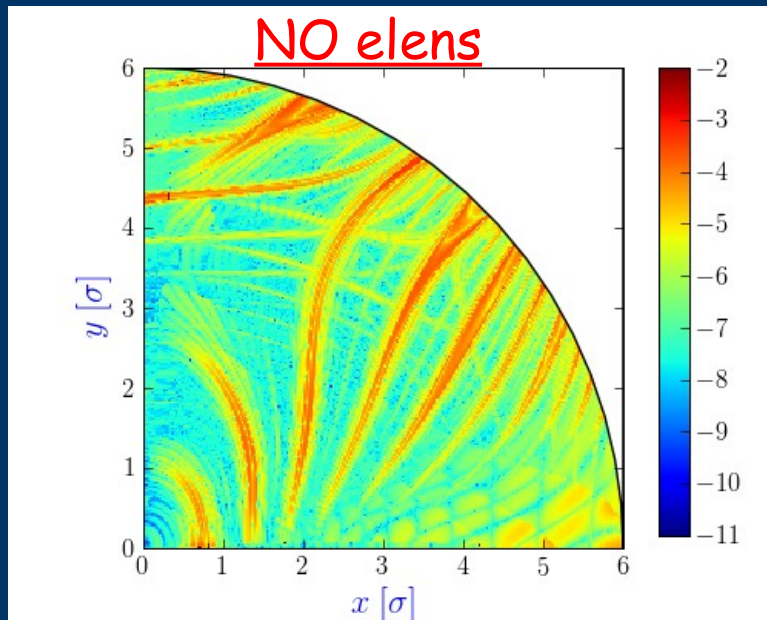
1x bbc fully compensates footprint
Footprint folding is observed.



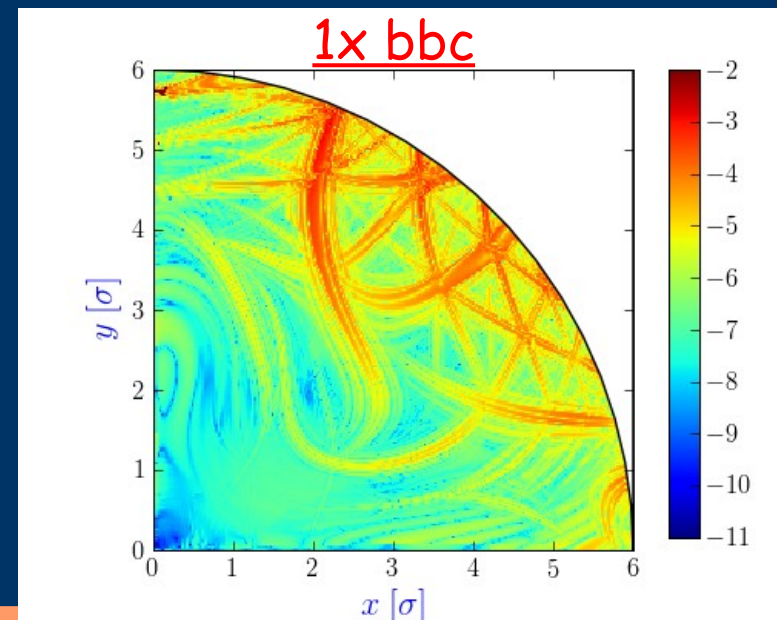
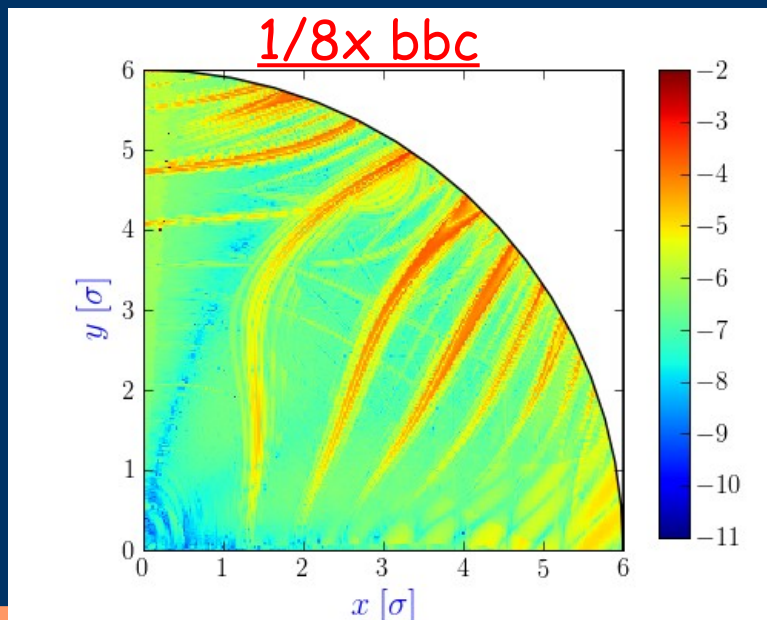
DA is increased at 1/8x bbc

- 1x bbc = beam-beam compensation with $N_e = N_{ip} * N_p = 2 * 2E11$

Gaussian Electron Lens (1 sigma)

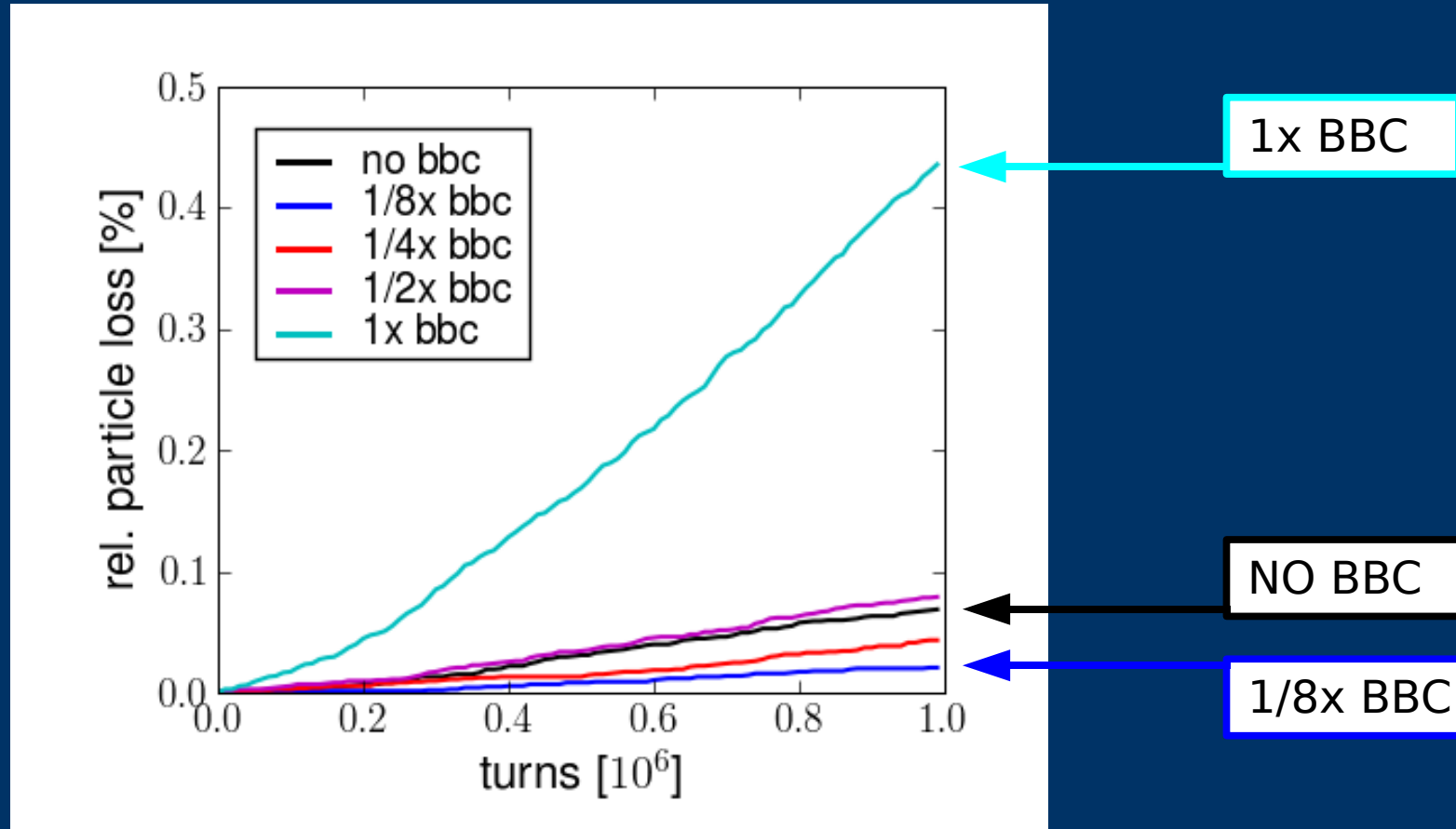


- Tune Diffusion: tune change btwn first and second 1024 turns
 - $DQ = \sqrt{dQx^2 + dQy^2}$
- 1x bbc: decrease tune change at small amp. but increase at large amp.
- 1/8x bbc: decrease tune change at both small and large amp.



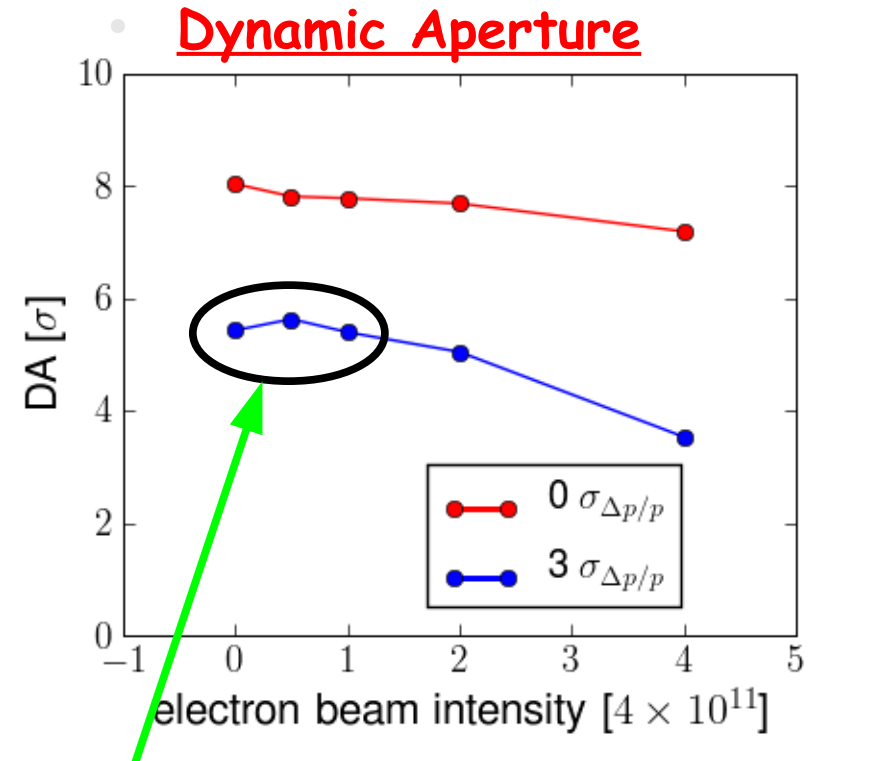
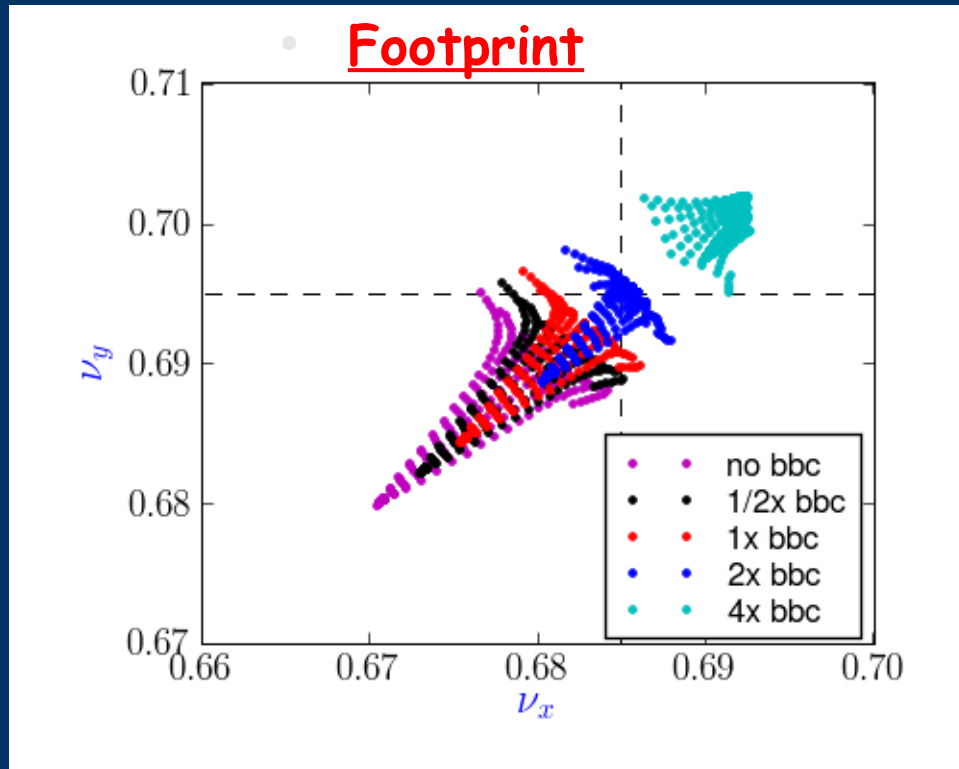
Gaussian Electron Lens (1 sigma)

- Particle loss



- Small N_e reduces beam loss: $N_e < 0.5 N_{ip} * N_p$
 - (loss with 1x bbc)/(loss with NO bbc) ~ 600%
 - (loss with 1/8x bbc)/(loss with NO bbc) ~ 30%

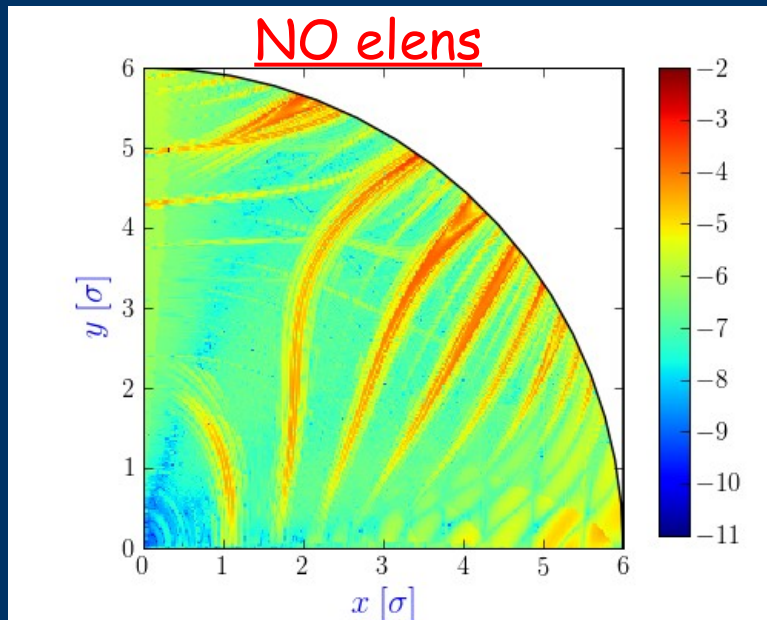
Gaussian Electron Lens (2 sigma)



DA is increased at 1/2x bbc

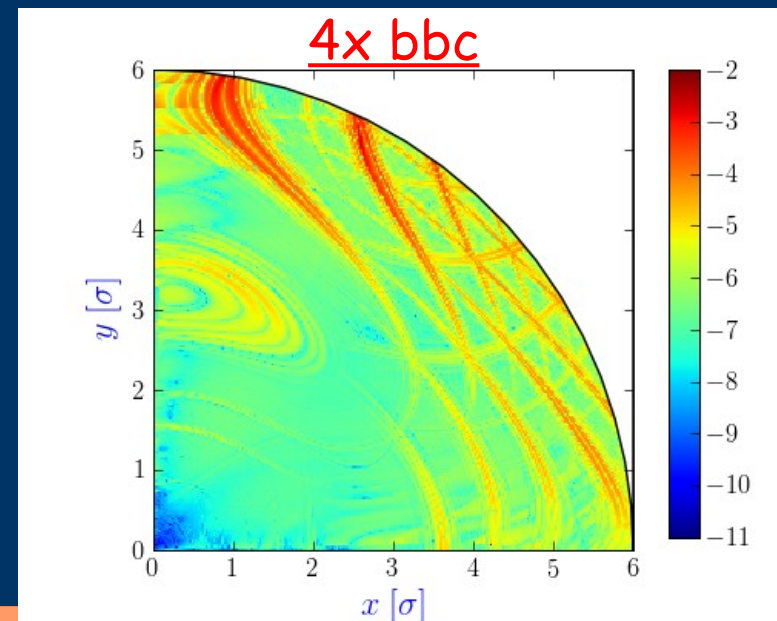
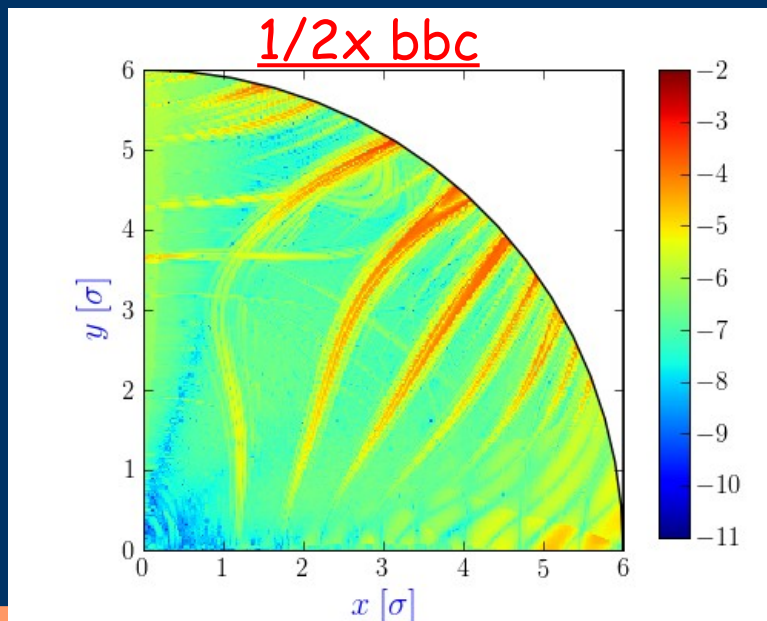
- Peak of 4x bbc electron beam profile is matched to that of 1x bbc at 1 sigma Gaussian.

Gaussian Electron Lens (2 sigma)



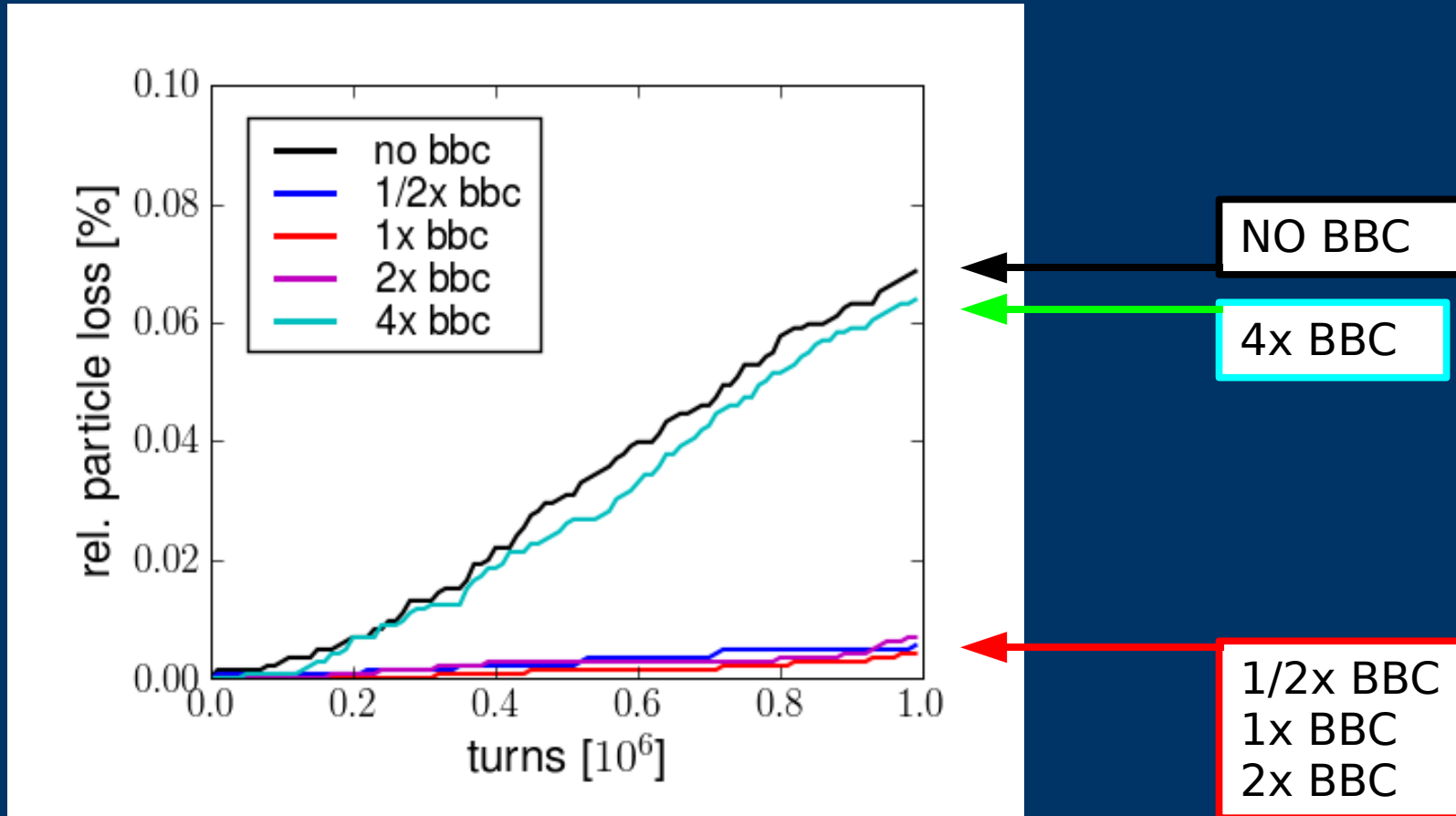
- Tune Diffusion

- 4x bbc: decrease tune change at small amp. but increase at large amp.
- 1/2x bbc: decrease tune change at both small and large amp.



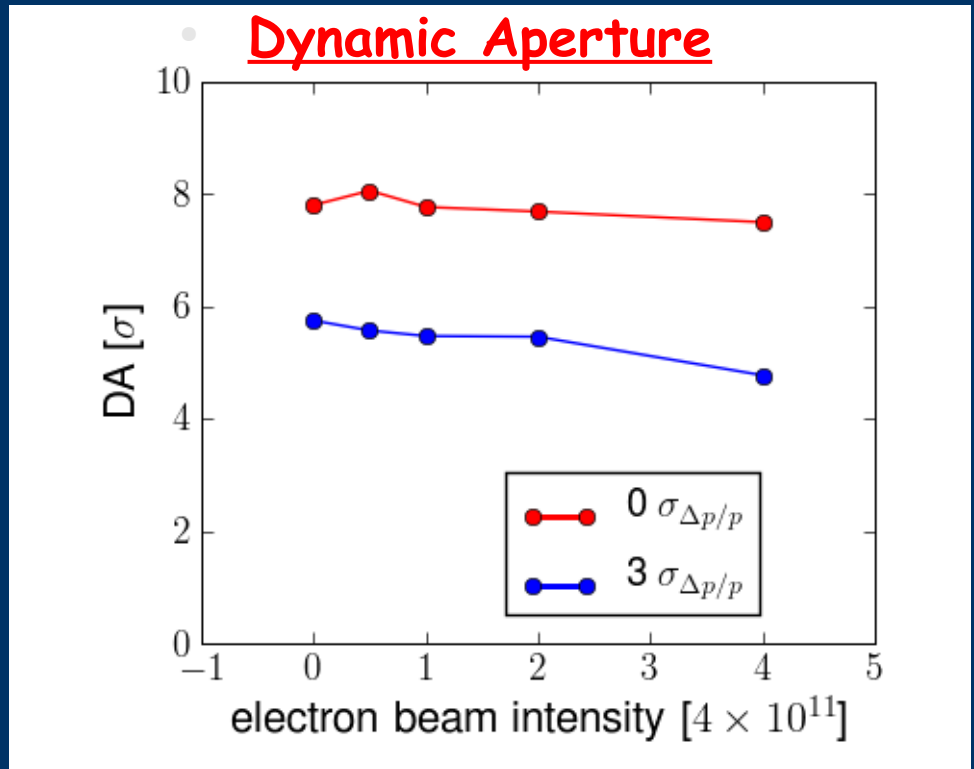
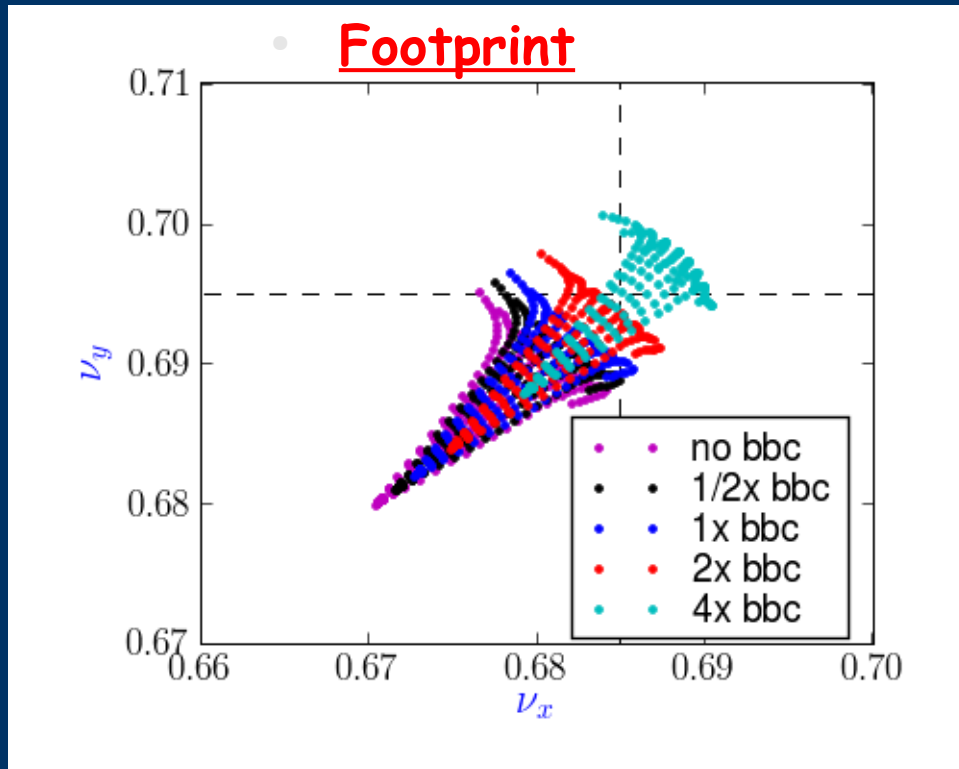
Gaussian Electron Lens (2 sigma)

- Particle loss



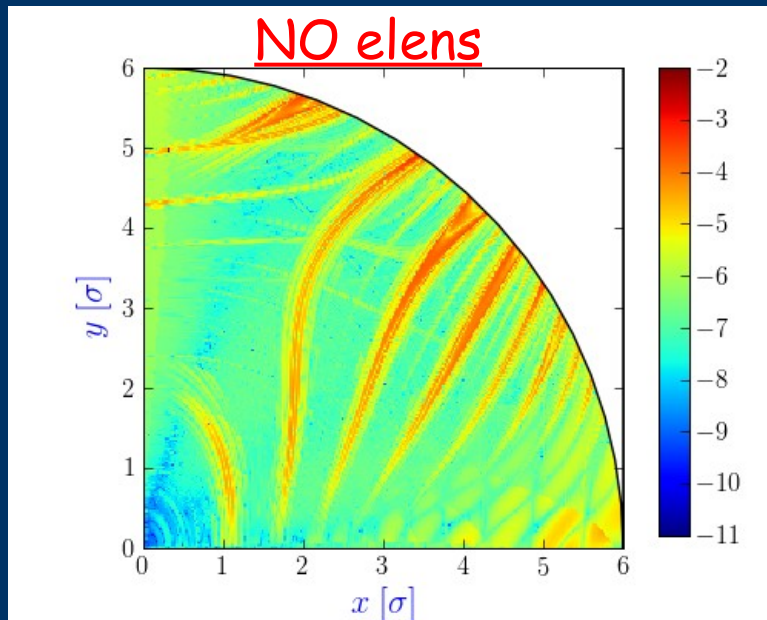
- Small N_e reduces beam loss:
 - $(\text{loss with } 1/2x \text{ bbc}) / (\text{loss with NO bbc}) \sim 10\%$

SEFT Electron Lens (4 sigma)



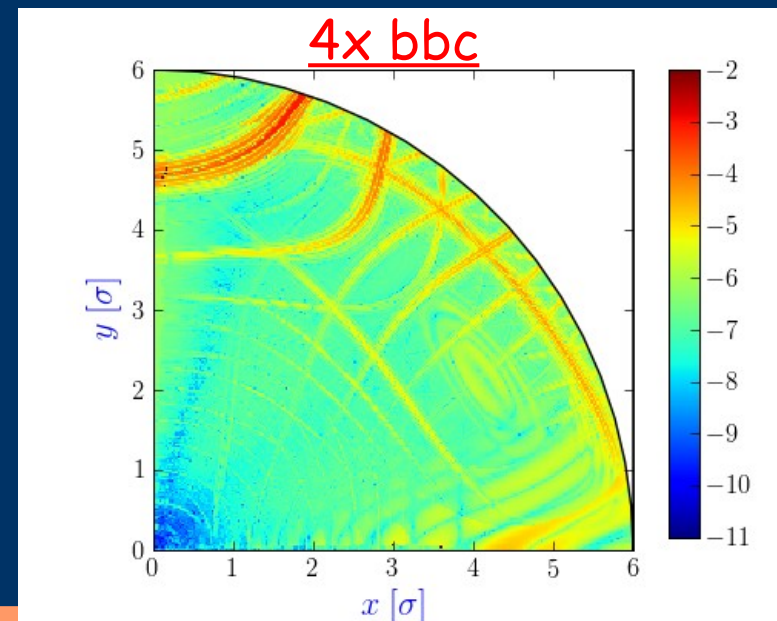
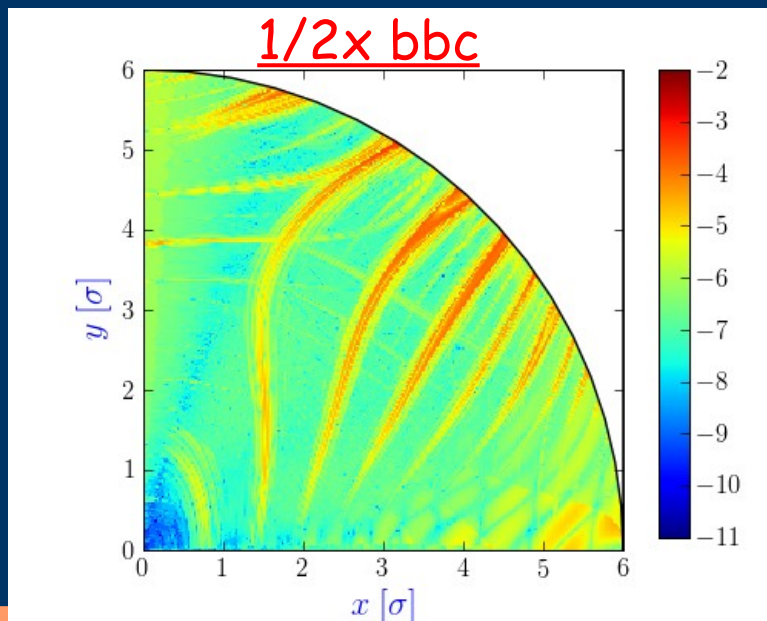
- Shape of footprint with compensation is almost the same as without compensation.
- Dynamic aperture is almost the same up to 2x bbc.

SEFT Electron Lens (4 sigma)



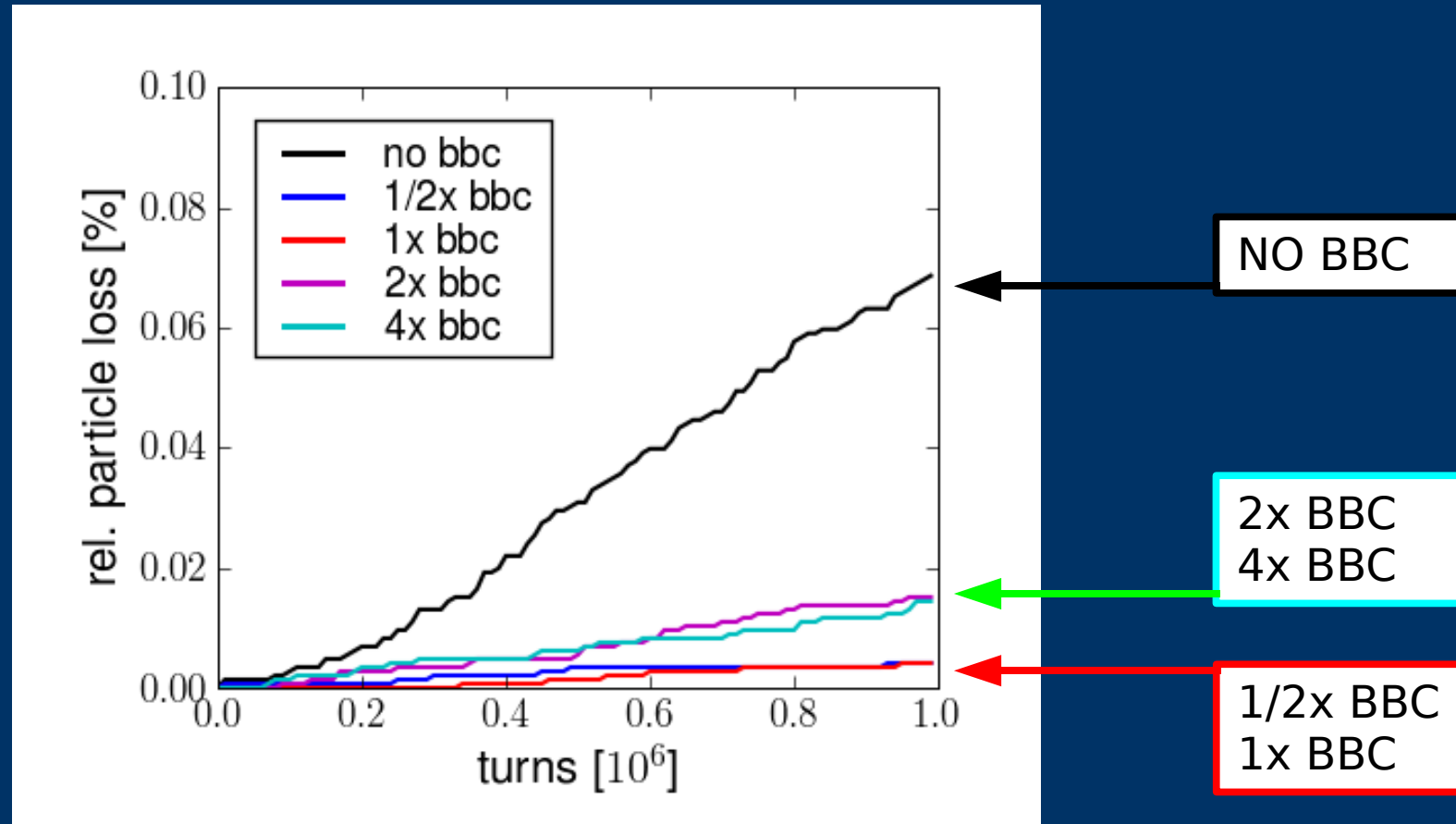
- Tune Diffusion

- 4x bbc: decrease tune change at small amp. but increase at large amp.
- 1/2x bbc: decrease tune change at both small and large amp.



SEFT Electron Lens (4 sigma)

- Particle loss



- Small Ne reduces beam loss:
 - (loss of 1/2x bbc)/(loss of NO bbc) \sim 10%

Comparison of electron beam distributions

Profile	Intensity (N _{ip} *N _p)	Dynamic aperture (sigma)	Particle loss (Relative to NO elens)
1 sigma Gaussian	1/2	5.10	115%
	1/4	5.44	63%
	1/8	5.63	30%
2 sigma Gaussian	2	5.05	10%
	1	5.40	8%
	1/2	5.63	6%
SEFT	2	4.77	22%
	1	5.47	6%
	1/2	5.57	6%

- Particle loss is relatively insensitive to electron lens current variations below threshold current with 2 sigma Gaussian and SEFT profiles.

Summary

- Full tune-spread compression also causes footprint folding and increases particle loss. Partial tune-spread compression without inducing footprint folding may reduce particle loss.
- Tune diffusion is closely related to particle loss.
- There is a threshold electron beam intensity below which beam life time is increased

Profile	Threshold ($N_{ip} \cdot N_p$)
1 sigma G	0.5
2 sigma G	2
SEFT	4

- Particle losses for 2 sigma Gaussian and SEFT profiles are relatively insensitive to intensities below threshold.
- Wider electron beam profile than proton at elens location is found to increase beam life time. Validation with better statistics in progress.